P-Channel Enhancement Mode Field Effect Transistor

- **Features**

V_{DS} (V) = -30V

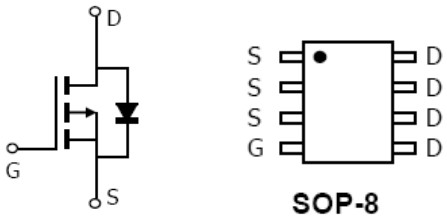
I_D = -12 A (V_{GS} = -20V)

$R_{DS(ON)}$ < 13mΩ(V_{GS} = -20V)

$R_{DS(ON)}$ < 14mΩ (V_{GS} = -10V)

$R_{DS(ON)}$ < 38mΩ (V_{GS} = -5V)

- **Pin Configurations**



SOP-8

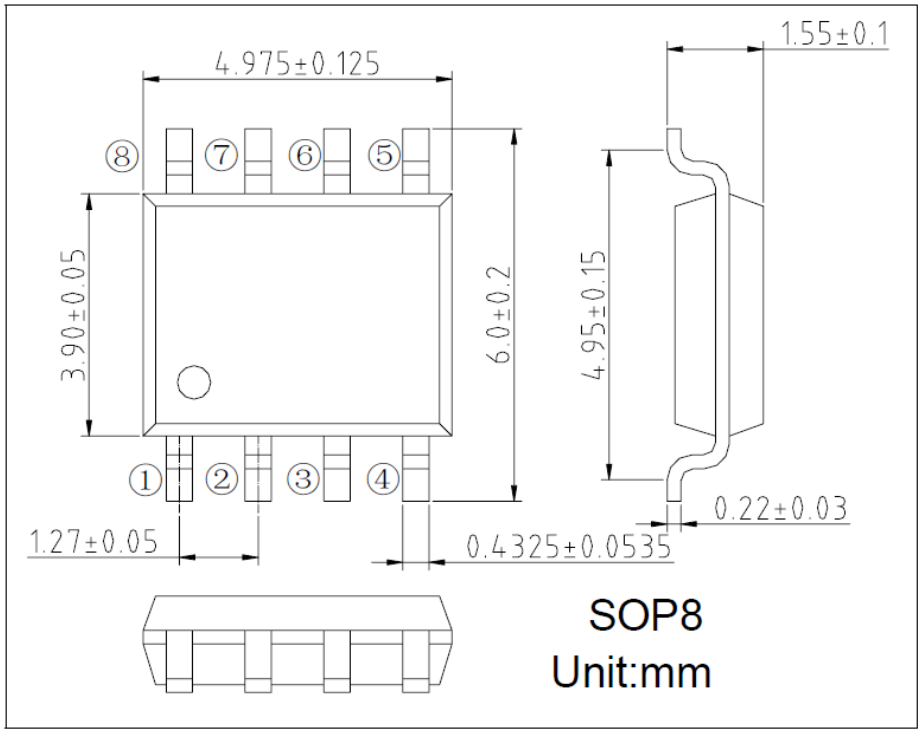
- **General Description**

The HX4407SQ/L uses advanced trench technology to provide excellent $R_{DS(ON)}$, and ultra-low low gate charge with a 25V gate rating. This device is suitable for use as a load switch or in PWM applications.HX4407SQ and HX4407SQL are electrically identical.

-RoHS Compliant

-HX4407SQL is Halogen Free

- **Package Information**



- **Absolute Maximum Ratings** @T_A=25℃ unless otherwise noted

Parameter		Symbol	Ratings	Unit
Drain-Source Voltage		V_{DSS}	-30	V
Gate-Source Voltage		V_{GSS}	±25	V
Drain Current (Continuous) *AC	T_A=25°C	I_D	-12	A
	T_A=70°C		-10	
Drain Current (Pulse) *B		I_{DM}	-60	A
Power Dissipation	T_A=25°C	P_D	3	W
	T_A=70°C		2.1	
Operating Temperature/ Storage Temperature		T_J/T_{STG}	-55~150	℃

- **Electrical Characteristics** @T_A=25℃ unless otherwise noted

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Static						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	V_{GS} = 0V, I_D= -250μA	-30	--	--	V
Zero Gate Voltage Drain Current	I_{DSS}	V_{DS} = -30 V, V_{GS} = 0V	--	--	-1	μA
Gate Threshold Voltage	V_{GSS}	V_{GS} = V_{DS}, I_{DS}= -250μA	-1.6	-1.8	-3	V
Gate Leakage Current	I_{GSS}	V_{GS} =±25V, V_{DS}=0V	--	--	100	nA
Drain-Source On-state Resistance	$R_{DS(on)}$	V_{GS} = -10V, I_D = -10A	--	11	14	mΩ
		V_{GS} = -20V, I_D = -10A	--	10	13	mΩ
		V_{GS} = -5V, I_D = -10A	--	27	38	mΩ
Forward Transconductance	g_{FS}	V_{DS} = -5V, I_D = -10A	--	26	--	S
Diode Forward Voltage	V_{SD}	I_{SD} = -1A , V_{GS}=0V	--	-0.72	-1.0	V
Maximum Body-Diode Continuous Current	I_S		--	--	-4.2	A
Switching						
Total Gate Charge	Q_g	V_{GS}= -10V, V_{DS}= -15V, I_D= -12A	30	37.2	45	nC
Gate-Source Charge	Q_{gs}		--	7	--	nC
Gate-Drain Charge	Q_{gd}		--	10.4	--	nC
Turn-on Delay Time	$t_{d(on)}$	V_{GS}=-10V,V_{DS}= -15V, R_L=1.25Ω, R_{GEN}=3Ω	--	12.4	--	ns
Turn-off Delay Time	$t_{d(off)}$		--	25.6	--	ns
Dynamic						
Input Capacitance	Ciss	V_{GS}=0V, V_{DS}= -15V, f=1MHz	--	2076	2500	pF
Output Capacitance	Coss		--	503	--	pF
Reverse Transfer Capacitance	Crss		--	302	423	pF

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1in 2 FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The value in any given application depends on the user's specific board design.

B: Repetitive rating, pulse width limited by junction temperature.

C: The current rating is based on the t≤ 10s junction to ambient thermal resistance rating.

- **TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

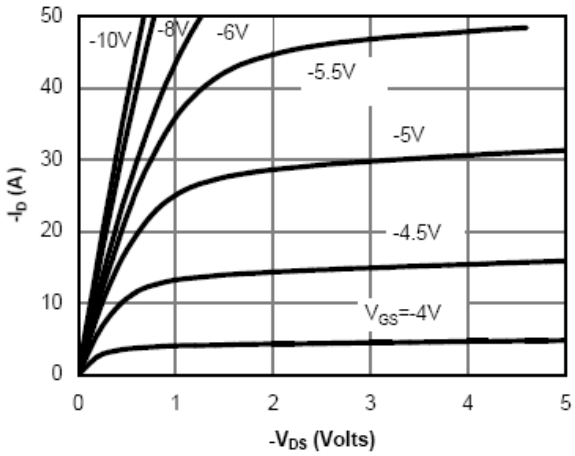


Fig 1: On-Region Characteristics

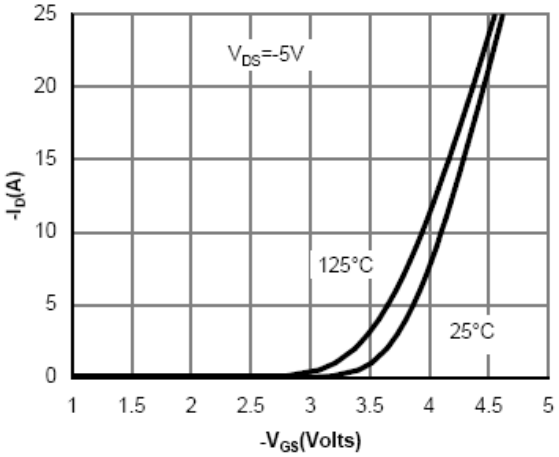


Figure 2: Transfer Characteristics

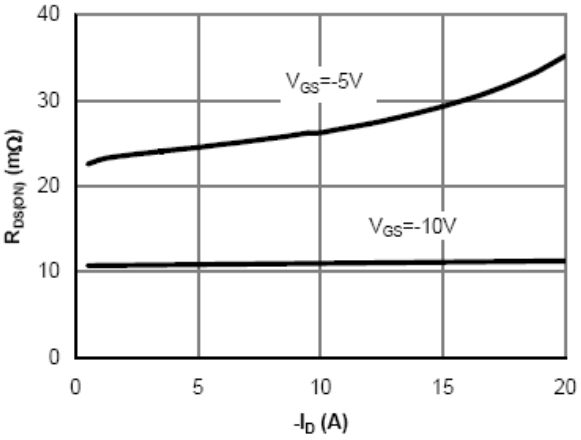


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

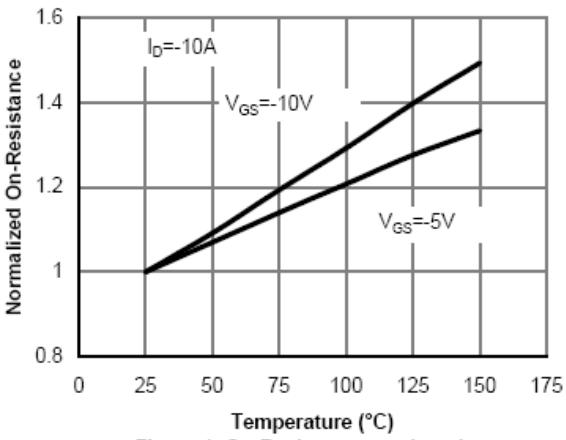


Figure 4: On-Resistance vs. Junction Temperature

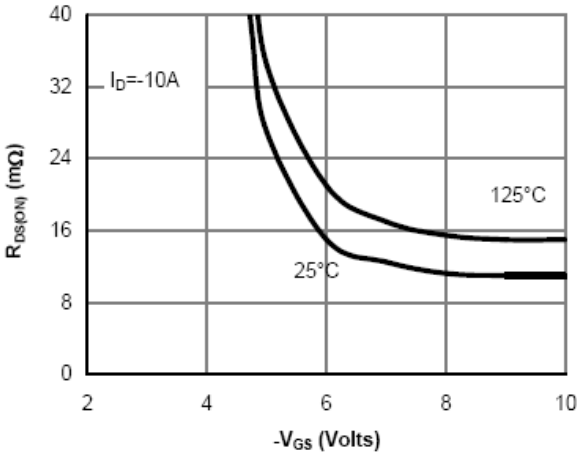


Figure 5: On-Resistance vs. Gate-Source Voltage

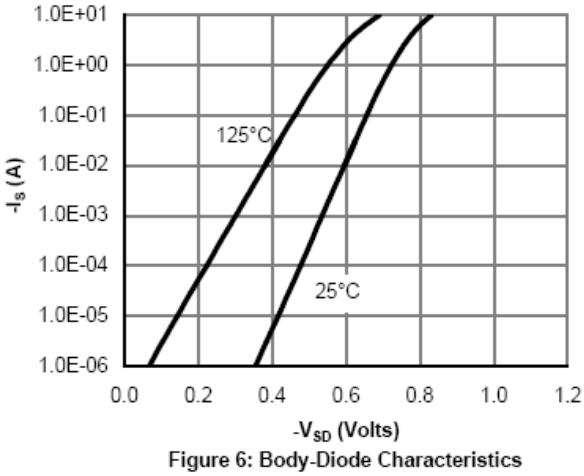


Figure 6: Body-Diode Characteristics

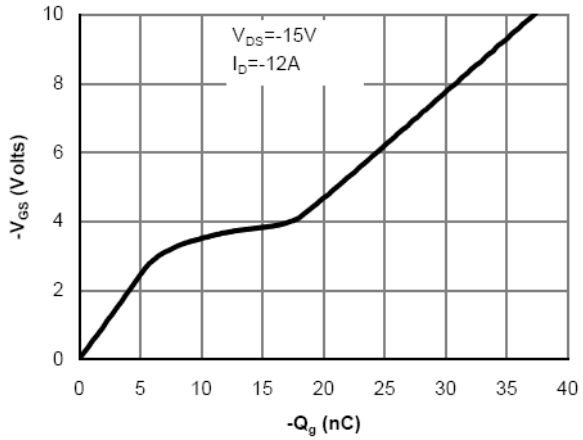


Figure 7: Gate-Charge Characteristics

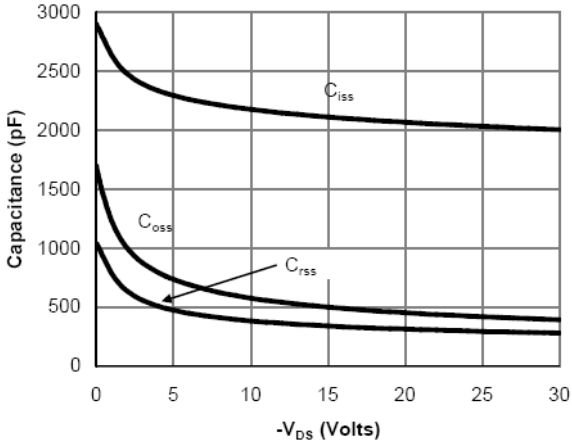


Figure 8: Capacitance Characteristics

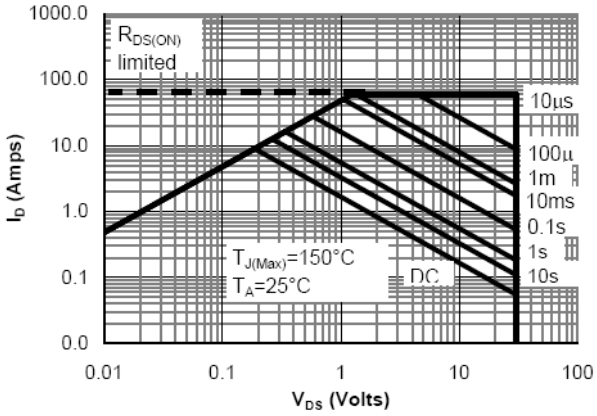


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

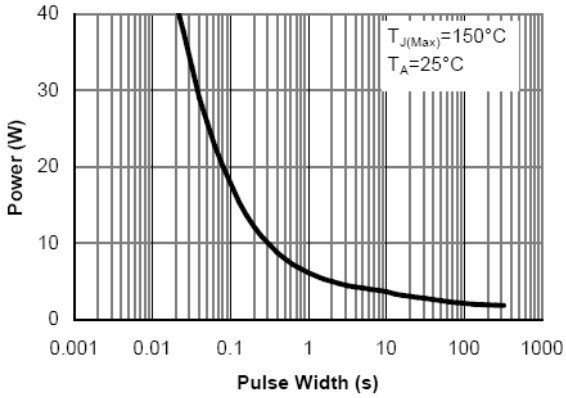


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

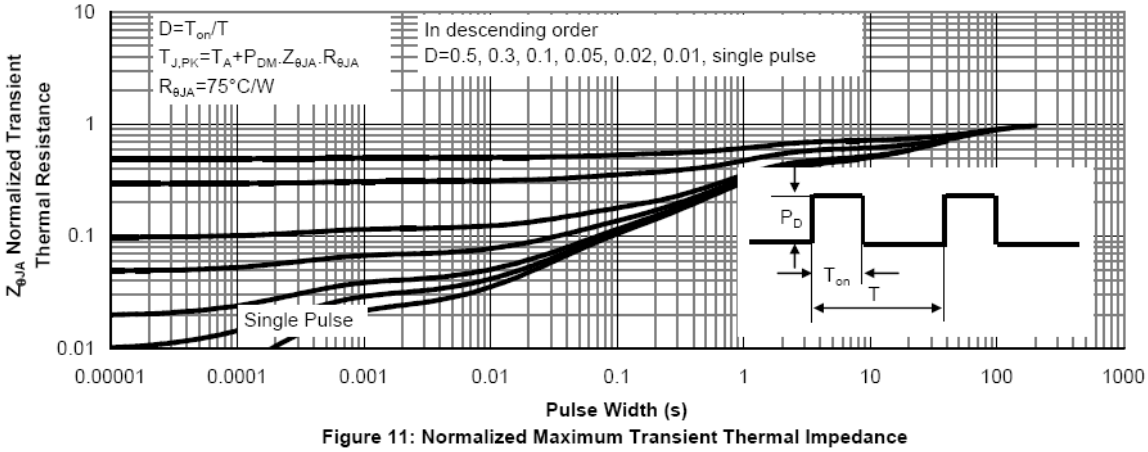


Figure 11: Normalized Maximum Transient Thermal Impedance

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